

# SEMiX® 3s

### Trench IGBT Modules

#### SEMiX453GB12E4s

#### **Features**

- · Homogeneous Si
- Trench = Trenchgate technology
- V<sub>CE(sat)</sub> with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

### **Typical Applications\***

- · AC inverter drives
- UPS
- Electronic Welding

#### **Remarks**

- Case temperature limited to T<sub>C</sub>=125°C max.
- Product reliability results are valid for T<sub>j</sub>=150°C
- Dynamic values apply to the following combination of resistors:

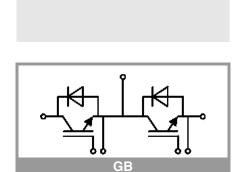
 $R_{Gon,main} = 1.0 \Omega$ 

 $R_{Goff,main} = 1.0 \Omega$ 

 $R_{G,X} = 2,2 \Omega$ 

 $R_{E,X} = 0.5 \Omega$ 

 For storage and case temperature with TIM see document "TP(\*) SEMiX 3s"



Absolute Maximum Ratings							
Symbol	Conditions		Values	Unit			
IGBT			•				
V <sub>CES</sub>	T <sub>j</sub> = 25 °C		1200	V			
Ic	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	683	Α			
		T <sub>c</sub> = 80 °C	526	Α			
I <sub>Cnom</sub>			450	Α			
I <sub>CRM</sub>	$I_{CRM} = 3xI_{Cnom}$		1350	Α			
$V_{GES}$			-20 20	V			
t <sub>psc</sub>	$V_{CC} = 800 \text{ V}$ $V_{GE} \le 15 \text{ V}$ $V_{CES} \le 1200 \text{ V}$	T <sub>j</sub> = 150 °C	10	μs			
T <sub>j</sub>			-40 175	°C			
Inverse di	iode						
$V_{RRM}$	T <sub>j</sub> = 25 °C		1200	V			
l <sub>F</sub>	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	544	Α			
		T <sub>c</sub> = 80 °C	407	Α			
I <sub>Fnom</sub>			450	Α			
I <sub>FRM</sub>	I <sub>FRM</sub> = 3xI <sub>Fnom</sub>		1350	Α			
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms, sin 180°, T <sub>j</sub> = 25 °C		2430	Α			
Tj			-40 175	°C			
Module							
I <sub>t(RMS)</sub>			600	Α			
T <sub>stg</sub>	module without TIM		-40 125	°C			
V <sub>isol</sub>	AC sinus 50Hz, t =	1 min	4000	V			

Characteristics							
Symbol	Conditions		min.	typ.	max.	Unit	
IGBT	'						
$V_{CE(sat)}$ $I_C = 450 \text{ A}$ $V_{GE} = 15 \text{ V}$ chiplevel	_	T <sub>j</sub> = 25 °C		1.80	2.05	V	
	~-	T <sub>j</sub> = 150 °C		2.19	2.40	V	
V <sub>CE0</sub>	chiplevel	T <sub>j</sub> = 25 °C		0.8	0.9	V	
		T <sub>j</sub> = 150 °C		0.7	0.8	V	
r <sub>CE</sub>	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25 °C		2.2	2.6	mΩ	
chiplevel	chiplevel	T <sub>j</sub> = 150 °C		3.3	3.6	mΩ	
$V_{\text{GE(th)}}$	$V_{GE}=V_{CE}$ , $I_{C}=18$ mA		5	5.8	6.5	V	
I <sub>CES</sub>	$V_{GE} = 0 \text{ V}, V_{CE} = 12$	00 V, T <sub>j</sub> = 25 °C			5	mA	
C <sub>ies</sub>	), o=),	f = 1 MHz		27.9		nF	
Coes	V <sub>CE</sub> = 25 V V <sub>GF</sub> = 0 V	f = 1 MHz		1.74		nF	
C <sub>res</sub>	VGE - O V	f = 1 MHz		1.53		nF	
$Q_{G}$	V <sub>GE</sub> = - 8 V+ 15 V			2550		nC	
$R_{\text{Gint}}$	T <sub>j</sub> = 25 °C			1.7		Ω	
t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V	T <sub>j</sub> = 150 °C		336		ns	
t <sub>r</sub>	$\begin{array}{l} I_{C} = 450 \text{ A} \\ V_{GE} = +15/\text{-}15 \text{ V} \\ R_{G \text{ on}} = 1.9 \Omega \\ R_{G \text{ off}} = 1.9 \Omega \\ \text{di/dt}_{on} = 4000 \text{ A/}\mu\text{s} \\ \text{di/dt}_{off} = 5000 \text{ A/}\mu\text{s} \end{array}$	T <sub>j</sub> = 150 °C		80		ns	
E <sub>on</sub>		T <sub>j</sub> = 150 °C		45		mJ	
t <sub>d(off)</sub>		T <sub>j</sub> = 150 °C		615		ns	
t <sub>f</sub>		T <sub>j</sub> = 150 °C		130		ns	
E <sub>off</sub>		T <sub>j</sub> = 150 °C		66.5		mJ	
R <sub>th(j-c)</sub>	per IGBT				0.065	K/W	
R <sub>th(c-s)</sub>	per IGBT (λ <sub>grease</sub> =0.81 W/(m*K))			0.03		K/W	
R <sub>th(c-s)</sub>	per IGBT, pre-applied phase change material			0.021		K/W	



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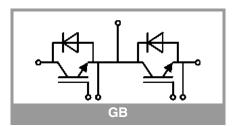
 $R_{Goff,main} = 1.0 \Omega$ 

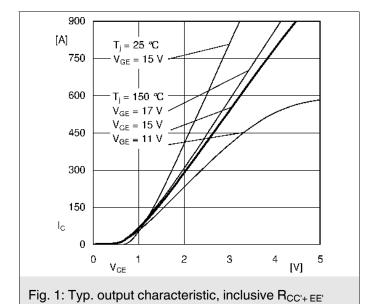
 $R_{G,X} = 2,2 \Omega$ 

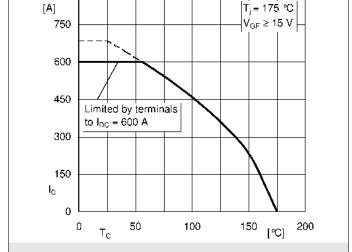
 $R_{E,X} = 0.5 \Omega$ 

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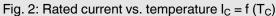
Characte	ristics					
Symbol	Conditions	min.	typ.	max.	Unit	
Inverse d	iode					1
$V_F = V_{EC}$	I <sub>F</sub> = 450 A	T <sub>j</sub> = 25 °C		2.14	2.46	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		2.07	2.38	V
V <sub>F0</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.30	1.50	V
		T <sub>j</sub> = 150 °C		0.90	1.10	V
r <sub>F</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.87	2.1	mΩ
		T <sub>j</sub> = 150 °C		2.6	2.8	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 450 A	T <sub>j</sub> = 150 °C		350		Α
$Q_{rr}$	di/dt <sub>off</sub> = 5000 A/μs V <sub>GE</sub> = -15 V	T <sub>j</sub> = 150 °C		70		μC
$E_{rr}$	$V_{CC} = 600 \text{ V}$	T <sub>j</sub> = 150 °C		28		mJ
R <sub>th(j-c)</sub>	per diode				0.11	K/W
R <sub>th(c-s)</sub>	per diode (λ <sub>grease</sub> =0	.81 W/(m*K))		0.045		K/W
R <sub>th(c-s)</sub>	per diode, pre-applied phase change material			0.036		K/W
Module						
L <sub>CE</sub>				20		nΗ
R <sub>CC'+EE'</sub>	measured per	T <sub>C</sub> = 25 °C		0.7		mΩ
	switch	T <sub>C</sub> = 125 °C		1		mΩ
Rth <sub>(c-s)1</sub>	calculated without thermal coupling			0.009		K/W
Rth <sub>(c-s)2</sub>	including thermal coupling, Ts underneath module $(\lambda_{grease}=0.81 \text{ W/} (\text{m*K}))$			0.013		K/W
Rth <sub>(c-s)2</sub>	including thermal coupling, Ts underneath module, pre-applied phase change material			0.01		K/W
Ms	to heat sink (M5)		3		5	Nm
Mt		to terminals (M6)	2.5		5	Nm
	1					Nm
W					300	g
Temperat	ure Sensor					
R <sub>100</sub>	T <sub>c</sub> =100°C (R <sub>25</sub> =5 kΩ)			493 ± 5%		Ω
B <sub>100/125</sub>	$R_{(T)} = R_{100} exp[B_{100/125}(1/T-1/T_{100})]; T[K];$			3550 ±2%		K

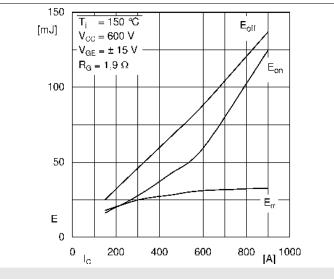


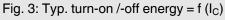




900







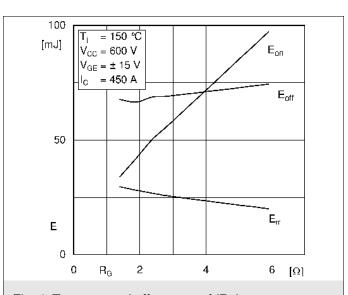
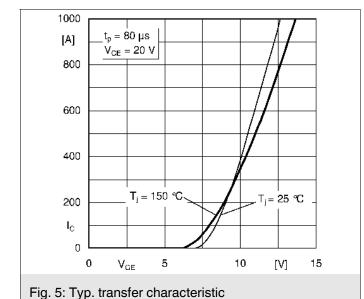
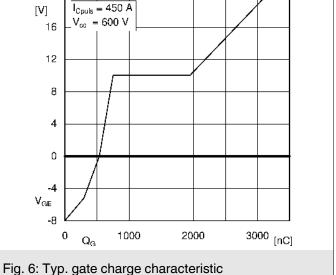
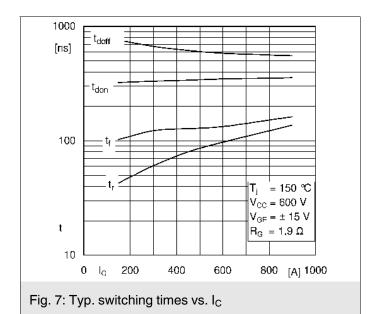


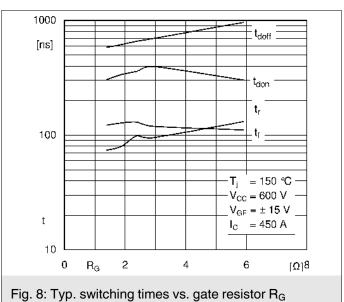
Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$ 

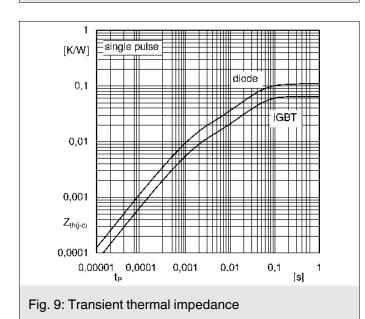
20

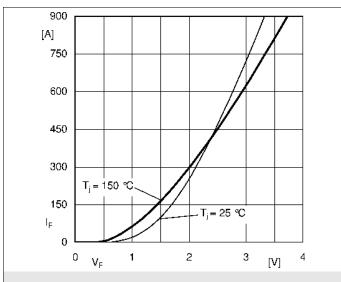












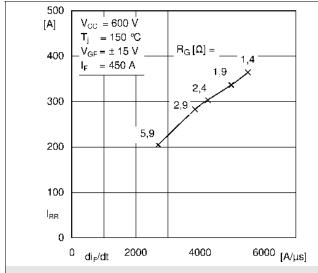
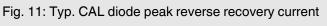


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{\text{CC}'\text{+ EE'}}$ 



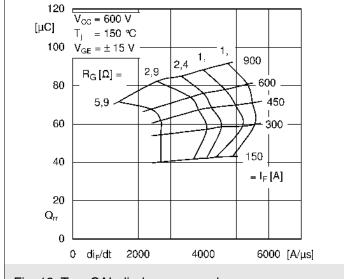
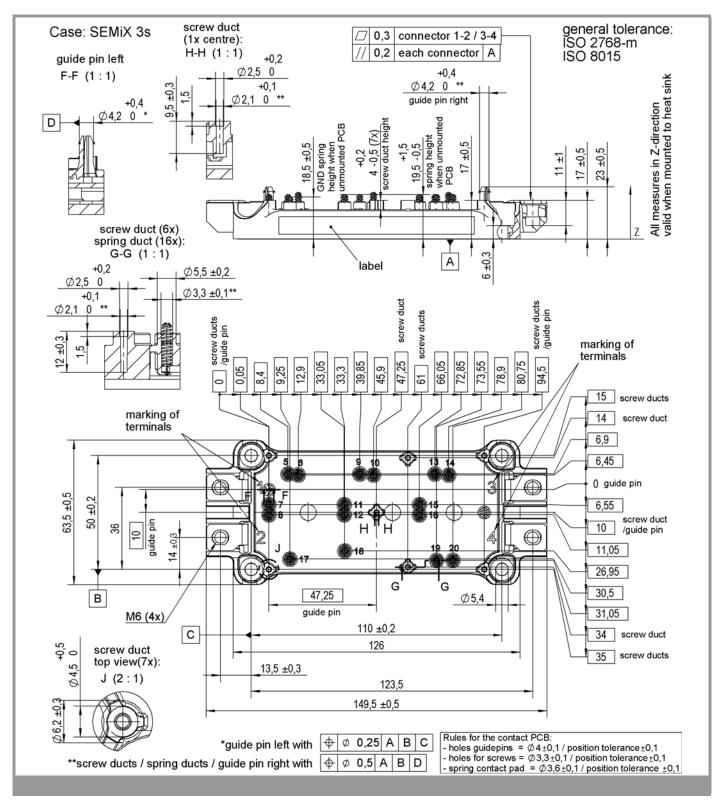
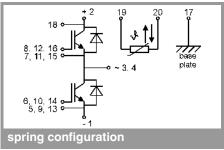


Fig. 12: Typ. CAL diode recovery charge





This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

#### \*IMPORTANT INFORMATION AND WARNINGS

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